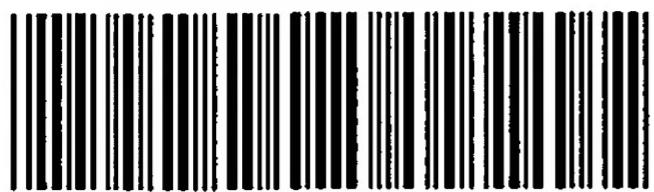


## **Search Notes**



**Application/Control No.**

10/043,276

**Examiner**

Junghwa M. Im

**Applicant(s)/Patent under  
Reexamination**

NAKATANI ET AL.

## **Art Unit**

2811

**SEARCHED**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**